OEAB

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56 CEAB

SN54GTL16616... WD PACKAGE

SN74GTL16616...DGG OR DL PACKAGE

(TOP VIEW)

- **Members of the Texas Instruments** Widebus™ Family
- Universal Bus Transceiver (UBT™) **Combines D-Type Latches and D-Type** Flip-Flops for Operation in Transparent, Latched, Clocked, or Clock-Enabled Mode
- **GTL Buffered CLKAB Signal (CLKOUT)**
- Translate Between GTL/GTL+ Signal Levels and LVTTL Logic Levels
- Support Mixed-Mode (3.3 V and 5 V) Signal **Operation on A-Port and Control Inputs**
- Equivalent to '16601 Function
- Ioff Supports Partial-Power-Down Mode Operation
- Bus Hold on Data Inputs Eliminates the **Need for External Pullup/Pulldown Resistors on A Port**
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- Distributed V_{CC} and GND-Pin Configuration **Minimizes High-Speed Switching Noise**
- **Package Options Include Plastic Shrink** Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Ceramic Flat (WD) Packages

description

The 'GTL16616 devices are 17-bit universal transceivers (UBTs) that

provide LVTTL-to-GTL/GTL+ and GTL/GTL+-to-LVTTL signal-level translation. They combine D-type

LEAB 🛛 2 55 CLKAB A1 🛮 3 54 🛮 B1 GND 4 53 GND A2 🛭 5 52 🛮 B2 A3 ∐ 6 51 ∐ B3 V_{CC} (3.3 V) **□**7 50 V_{CC} (5 V) A4 🛮 8 49 🛮 B4 48 🛮 B5 A5 L A6 L 10 ∏ B6 47 GND 11 46 GND A7 ∐ 12 45 ∐ B7 A8 🛮 13 B8 44 A9 ∐ 14 43 ll B9 A10 II 15 42 Π B10 A11 116 41 B11 A12 🛮 17 40 B12 GND II 18 🛮 GND 39 A13 | 19 38 **∏** B13 37 **∏** B14 A14 | 20 A15 🛮 21 36 B15 V_{CC} (3.3 V) **□**22 35 🛛 V_{REF} A16 Π 23 34 | B16 A17 124 33 B17 GND II 25 ∏ GND 32 CLKIN 26 31 CLKOUT OEBA 27 30 CLKBA 29 T CEBA LEBA ∏28

flip-flops and D-type latches to allow for transparent, latched, clocked, and clocked-enabled modes of data transfer identical to the '16601 function. Additionally, they provide for a copy of CLKAB at GTL/GTL+ signal levels (CLKOUT) and conversion of a GTL/GTL+ clock to LVTTL logic levels (CLKIN). The devices provide an interface between cards operating at LVTTL logic levels and a backplane operating at GTL/GTL+ signal levels. Higher-speed operation is a direct result of the reduced output swing (<1 V), reduced input threshold levels, and output edge control (OEC™).

The user has the flexibility of using this device at either GTL ($V_{TT} = 1.2 \text{ V}$ and $V_{RFF} = 0.8 \text{ V}$) or the preferred higher noise margin GTL+ ($V_{TT} = 1.5 \text{ V}$ and $V_{REF} = 1 \text{ V}$) signal levels. GTL+ is the Texas Instruments derivative of the Gunning transceiver logic (GTL) JEDEC standard JESD 8-3. The B port normally operates at GTL or GTL+ signal levels, while the A-port and control inputs are compatible with LVTTL logic levels and are 5-V tolerant. V_{REF} is the reference input voltage for the B port. V_{CC} (5 V) supplies the internal and GTL circuitry while V_{CC} (3.3 V) supplies the LVTTL output buffers.



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description (continued)

Data flow in each direction is controlled by output-enable (\overline{OEAB} and \overline{OEBA}), latch-enable (LEAB and LEBA), and clock (CLKAB and CLKBA) inputs. The clock can be controlled by the clock-enable (\overline{CEAB} and \overline{CEBA}) inputs. For A-to-B data flow, the device operates in the transparent mode when LEAB is high. When LEAB is low, the A data is latched if \overline{CEAB} is low and CLKAB is held at a high or low logic level. If LEAB is low, the A-bus data is stored in the latch/flip-flop on the low-to-high transition of CLKAB if \overline{CEAB} also is low. When \overline{OEAB} is low, the outputs are active. When \overline{OEAB} is high, the outputs are in the high-impedance state. Data flow for B to A is similar to that of A to B, but uses \overline{OEBA} , LEBA, CLKBA, and \overline{CEBA} .

These devices are fully specified for partial-power-down applications using I_{off}. The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

Active bus-hold circuitry holds unused or undriven LVTTL inputs at a valid logic state. Use of pullup or pulldown resistors with the bus-hold circuitry is not recommended.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54GTL16616 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74GTL16616 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE[†]

INPUTS					OUTPUT	MODE
CEAB	OEAB	LEAB	CLKAB	Α	В	MODE
Х	Н	Х	Х	Χ	Z	Isolation
L	L	L	H or L	Χ	в ₀ ‡	Latabad starage of A data
L	L	L	H or L	Χ	В ₀ §	Latched storage of A data
Х	L	Н	Х	L	L	Transparent
Х	L	Н	Χ	Н	Н	Transparent
L	L	L	↑	L	L	Classed storage of A data
L	L	L	\uparrow	Н	н	Clocked storage of A data
Н	L	L	Х	Х	B ₀ §	Clock inhibit

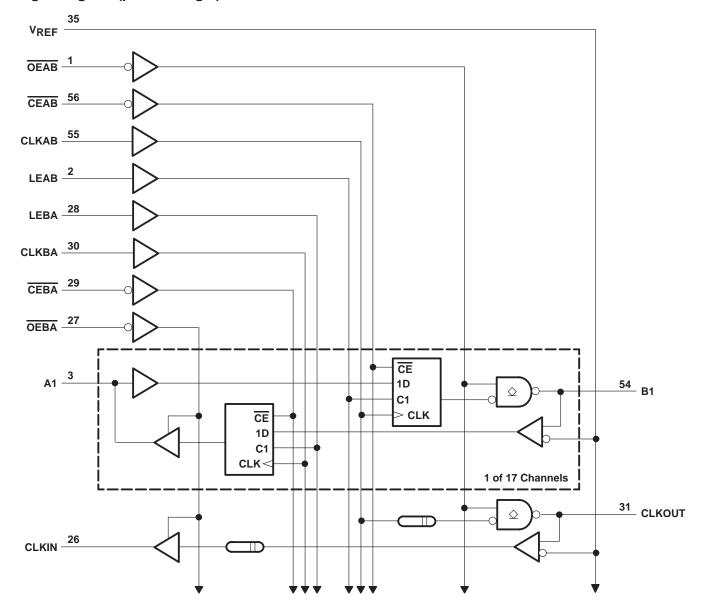
[†] A-to-B data flow is shown. B-to-A data flow is similar, but uses OEBA, LEBA, CLKBA, and CEBA.

[‡] Output level before the indicated steady-state input conditions were established, provided that CLKAB was high before LEAB went low

[§] Output level before the indicated steady-state input conditions were established

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logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC} : 3.3 V	
Input voltage range, V _I (see Note 1): A-port and control inputs	–0.5 V to 7 V
Voltage range applied to any output in the high or power-off state, V _O	
(see Note 1): A port	0.5 V to 7 V
B port	
Current into any output in the low state, IO: A port	
B port	
Current into any A-port output in the high state, I _O (see Note 2)	
Continuous current through each V _{CC} or GND	
Input clamp current, I _{IK} (V _I < 0)	
Output clamp current, I _{OK} (V _O < 0)	
Package thermal impedance, θ _{JA} (see Note 3): DGG package	
DL package	
Storage temperature range, T _{stg}	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 - 2. This current flows only when the output is in the high state and $V_O > V_{CC}$.
 - 3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Notes 4 through 6)

			SN54GTL16616			SN	UNIT		
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
V/00	Supply voltage	3.3 V	3.15	3.3	3.45	3.15	3.3	3.45	V
Vcc		5 V	4.75	5	5.25	4.75	5	5.25	V
\/	Termination	GTL	1.14	1.2	1.26	1.14	1.2	1.26	V
VTT	voltage	GTL+	1.35	1.5	1.65	1.35	1.5	1.65	V
\/	Cumply voltage	GTL	0.74	0.8	0.87	0.74	0.8	0.87	V
VREF	Supply voltage	GTL+	0.87	1 🔊	1.1	0.87	1	1.1	V
\/.	Input voltage	B port			VTT			VTT	V
VI		Except B port		Q	5.5			5.5	V
\/	High-level	B port	V _{REF} +50 m\	1 5		V _{REF} +50 mV			V
VIH	input voltage	Except B port	2	g_{Q}		2			V
\/	Low-level	B port		(A)	/ _{REF} -50 mV			V _{REF} -50 mV	V
VIL	input voltage	Except B port			0.8		1.14 1.2 1.26 1.35 1.5 1.65 0.74 0.8 0.87 0.87 1 1.1 VTT 5.5 EF+50 mV	V	
lik	Input clamp curren	t			-18			-18	mA
ІОН	High-level output current	A port			-32			-32	mA
	Low-level	A port			64			64	A
IOL	output current	B port			40			40	mA
T _A	Operating free-air t	emperature	– 55		125	-40		85	°C

NOTES: 4. All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

- 5. Normal connection sequence is GND first, $V_{CC} = 5 \text{ V}$ second, and $V_{CC} = 3.3 \text{ V}$, I/O, control inputs, V_{TT} and V_{REF} (any order) last.
- V_{TT} and R_{TT} can be adjusted to accommodate backplane impedances as long as they do not exceed the DC absolute I_{OL} ratings.
 Similarly, V_{RFF} can be adjusted to optimize noise margins, but normally is 2/3 V_{TT}.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADA	ACTED	TEST COND	ITIONS	SN54	GTL166	16	SN74	GTL1661	16	LINUT	
PARAI	METER	TEST COND	IIIONS	MIN TYP [†] MAX MIN T					MAX	UNIT	
VIK		V_{CC} (3.3 V) = 3.15 V, V_{CC} (5			-1.2			-1.2	V		
Vон	A port	V _{CC} (3.3 V)= 3.15 V to 3.45 V, V _{CC} (5 V) = 4.75 V to 5.25 V	I _{OH} = -100 μA	V _{CC} -0.2			V _{CC} -0.2			V	
011	'	V _{CC} (3.3 V) = 3.15 V,	I _{OH} = -8 mA	2.4			2.4				
		V _{CC} (5 V) = 4.75 V	I _{OH} = -32 mA	2			2				
			I _{OL} = 100 μA			0.2			0.2		
	A nom	V_{CC} (3.3 V) = 3.15 V,	I _{OL} = 16 mA			0.4			0.4		
VOL	A port	V_{CC} (5 V) = 4.75 V	I _{OL} = 32 mA			0.5			0.5	V	
VOL			I _{OL} = 64 mA			0.55			0.55	v	
	B port	V _{CC} (3.3 V) = 3.15 V, V _{CC} (5 V) = 4.75 V	I _{OL} = 40 mA			0.4			10 20 1 20 1 20 1 20 1 20 1 20 1 20 1 2		
	Control inputs	V _{CC} = 0 or 3.45 V, V _{CC} (5 V) = 0 or 5.25 V	V _I = 5.5 V			10			10		
	A port		V _I = 5.5 V			20			20		
l _l		V _{CC} (3.3 V) = 3.45 V, V _{CC} (5 V) = 5.25 V	$V_{I} = V_{CC} (3.3 \text{ V})$			1			1	μΑ	
·			V _I = 0		4	-30			-30	•	
	Donam	V _{CC} (3.3 V) = 3.45 V,	V _I = V _{CC} (3.3 V)	5							
	B port	V _{CC} (5 V) = 5.25 V	V _I = 0		200	-5			– 5		
l _{off}		$V_{CC} = 0$, V_{I} or $V_{O} = 0$ to 4.5 V_{O}	1		R	100			100	μΑ	
	A port	V _{CC} (3.3 V) = 3.15 V, V _{CC} (5 V) = 4.75 V	V _I = 0.8 V	75 \$)		75				
I _{I(hold)}			V _I = 2 V	-75		-75		μΑ			
, ,		VCC (3 V) = 4.73 V	$V_{I} = 0 \text{ to } V_{CC} (3.3 \text{ V})^{\ddagger}$	2		±500			-1.2 0.2 0.4 0.5 0.55 0.4 10 20 1 -30 5 -5 100 1 10 -1 -10 1 5 1 120 120 120 1 3.5 12		
1	A port	V_{CC} (3.3 V) = 3.45 V, V_{CC} (5	V) = 5.25 V, V _O = 3 V			1			1		
IOZH	B port	V_{CC} (3.3 V) = 3.45 V, V_{CC} (5	V) = 5.25 V, V _O = 1.2 V			10			10	μΑ	
10=1	A port	V_{CC} (3.3 V) = 3.45 V, V_{CC} (5	V) = 5.25 V, V _O = 0.5 V			-1			-1	μΑ	
IOZL	B port	V_{CC} (3.3 V) = 3.45 V, V_{CC} (5	V) = 5.25 V, V _O = 0.4 V			-10		TYPT MAX -1.2 0.2 0.4 0.5 0.55 0.4 10 20 1 -30 5 -5 100 11 -10 -11 -10 15 120 120 120 13.5 14 3.5	μΑ		
		V _{CC} (3.3 V) = 3.45 V,	Outputs high			1			5 -5 100 ±500 1 10 -1 -10 1 5		
(3.3 V)	A or B port	V_{CC} (5 V) = 5.25 V, I_{O} = 0,	Outputs low			5			5	mA	
(3.3 V)	Port	$V_I = V_{CC}$ (3.3 V) or GND	Outputs disabled			1			1		
	I	V _{CC} (3.3 V) = 3.45 V,	Outputs high			120			120		
ICC (5 V)	A or B port	V_{CC} (5 V) = 5.25 V, I_{O} = 0,	Outputs low			120			120	mA	
(0)	Port	$V_I = V_{CC}$ (3.3 V) or GND	Outputs disabled			120			0.55 0.4 10 20 1 -30 5 -5 100 1 10 21 100 11 10 11 5 11 120 120		
Δl _{CC} §		V _{CC} (3.3 V) = 3.45 V, V _{CC} (5 A-port or control inputs at V _{CC} One input at 2.7 V				1			1	mA	
C _i	Control inputs	V _I = 3.15 V or 0			3.5			3.5		pF	
C	A port	V _O = 3.15 V or 0			12			12		nΕ	
C _{io}	B port	Per IEEE Std 1194.1				5			5	pF	

[†] All typical values are at V_{CC} (3.3 V) = 3.3 V, V_{CC} (5 V) = 5 V, T_A = 25°C.



[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] This is the increase in supply current for each input that is at the specified TTL voltage level rather than VCC or GND.

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timing requirements over recommended ranges of supply voltage and operating free-air temperature, $V_{TT} = 1.2 \text{ V}$ and $V_{REF} = 0.8 \text{ V}$ for GTL (unless otherwise noted) (see Figure 1)

			SN54GTI	_16616	SN74GTL	16616	UNIT
			MIN MAX		MIN	MAX	UNIT
f _{clock}	Clock frequency			95		95	MHz
	Pulse duration	LEAB or LEBA high	3.3		3.3		20
t _W	ruise duration	CLKAB or CLKBA high or low	5.5		5.5		ns
		A before CLKAB↑	1.3		1.3		
	Setup time	B before CLKBA↑	2.5	FIN	2.5		
		A before LEAB↓	0	T.	0		
t _{su}		B before LEBA↓	1.1 4	Σ. Σ.	1.1		ns
		CEAB before CLKAB↑	2.2		2.2		
		CEBA before CLKBA↑	2.7		2.7		
		A after CLKAB↑	1.6		1.6		
		B after CLKBA↑	0.4		0.4		
4.	Hold time	A after LEAB↓	4		4		
th	noid time	B after LEBA↓	3.5		3.5		ns
		CEAB after CLKAB↑	1.1		1.1		
		CEBA after CLKBA↑	0.9		0.9		

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, V_{TT} = 1.2 V and V_{REF} = 0.8 V for GTL (see Figure 1)

PARAMETER	FROM	то	SN5	SN54GTL16616			SN74GTL16616		
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNIT
f _{max}			95			95			MHz
^t PLH	А	В	1.4	3	4.6	1.7	3	4.4	ns
^t PHL	A	В	1.2	2.8	4.7	1.4	2.8	4.5	115
^t PLH	LEAB	В	2.1	3.8	5.6	2.3	3.8	5.4	ns
^t PHL		В	1.9	3.7	5.6	2.2	3.7	5.3	115
^t PLH	CLKAB	В	2.2	4	5.9	2.4	4	5.7	ns
^t PHL		Ь	1.8	3.7	5.7	2.1	3.7	5.4	115
^t PLH	CLKAB	CLKOUT	4.5	6.1	8.2	4.7	6.1	8.1	ns
^t PHL		CLROUT	5.5	7.9	11.4	5.7	7.9	11.3	115
^t dis	ŌEAB	B or CLKOUT	2	3.8	5.8	2.1	3.8	5.6	ns
t _{en}			2	3.6	5.2	2.1	3.6	5.1	115
t _r	Transition time, B or	utputs (0.5 V to 1 V)		\$ 1.2			1.2		ns
t _f	Transition time, B or	utputs (1 V to 0.5 V)	ć	0.7			0.7		ns
^t PLH	В	Α	1.6	4	6.8	1.7	4	6.7	ns
^t PHL	Ь	Λ	1.3	2.9	4.7	1.4	2.9	4.7	115
^t PLH	LEBA	А	2.3	3.8	6.1	2.4	3.8	5.8	ns
^t PHL	LLDA	Λ	1.9	3	4.8	2	3	4.6	115
^t PLH	CLKBA	А	2.5	4	6.3	2.6	4	6	ns
^t PHL	OLNDA	Λ	2.1	3.4	5.1	2.2	3.4	4.9	115
t _{PLH}	CLKOUT	CLKIN	7.2	10	14.7	7.4	10	14.4	ns
^t PHL	OLINOOT	OLIVIIV	5.9	8.1	11.8	6.1	8.1	11.7	113
t _{en}	OEBA	A or CLKIN	2.7	5.3	8.1	2.8	5.3	7.8	ns
^t dis	OLBA	7. OI OLIVIIV	2.6	4.3	6.7	2.7	4.3	6.4	110

 $[\]dagger$ All typical values are at V_{CC} (3.3 V) = 3.3 V, V_{CC} (5 V) = 5 V, T_A = 25°C.

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timing requirements over recommended ranges of supply voltage and operating free-air temperature, V_{TT} = 1.5 V and V_{REF} = 1 V for GTL+ (unless otherwise noted) (see Figure 1)

			MIN MAX		SN74GTL	UNIT			
					MIN	MAX	UNIT		
fclock	Clock frequency			95		95	MHz		
	Pulse duration	LEAB or LEBA high	3.3		3.3		ns		
t _W	Fuise duration	CLKAB or CLKBA high or low	5.5		5.5		115		
		A before CLKAB↑	1.3		1.3				
	Setup time	B before CLKBA↑	2.3	N.	2.3				
		A before LEAB↓	0	7.	0				
t _{su}		B before LEBA↓	1.3	Q2"	1.3		ns		
		CEAB before CLKAB↑	2.2		2.2				
		CEBA before CLKBA↑	2.7		2.7				
		A after CLKAB↑	29.6		1.6				
		B after CLKBA↑	0.6		0.6				
4.	Hold time	A after LEAB↓	4		4				
th	noid little	B after LEBA↓	3.5		3.5		ns		
		CEAB after CLKAB↑	1.1		1.1				
		CEBA after CLKBA↑	0.9		0.9				

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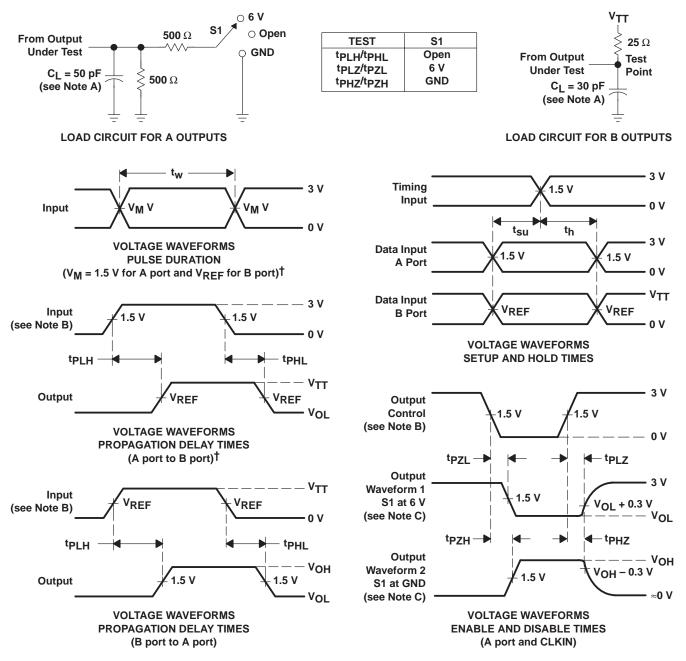
switching characteristics over recommended ranges of supply voltage and operating free-air temperature, V_{TT} = 1.5 V and V_{REF} = 1 V for GTL+ (see Figure 1)

DADAMETED	FROM	то	SN5	SN54GTL16616			SN74GTL16616		
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNIT
f _{max}			95			95			MHz
^t PLH	_	В	1.4	3	4.6	1.7	3	4.4	ns
^t PHL	A	Б	1.2	2.9	4.8	1.4	2.9	4.6	115
^t PLH	LEAB	В	2.1	3.8	5.6	2.3	3.8	5.4	
^t PHL	LEAB	Ь	1.9	3.7	5.7	2.2	3.7	5.4	ns
^t PLH	CLKAB	В	2.2	4	5.9	2.4	4	5.7	ns
^t PHL	CLNAD	Ь	1.8	3.8	5.8	2.1	3.8	5.5	115
^t PLH	CLKAB	CLKOUT	4.5	6.1	8.2	4.7	6.1	8.1	ns
^t PHL	CLNAD	CLKOUT	5.5	8	11.5	5.7	8	11.4	115
^t PLH	OEAB	B or CLKOUT	2	3.6	5.2	2.1	3.6	5.1	ns
^t PHL			2	3.8	5.9	2.1	3.8	5.7	115
t _r	Transition time, B or	utputs (0.5 V to 1 V)		\$ 1.4			1.4		ns
t _f	Transition time, B or	utputs (1 V to 0.5 V)	ć	9 1			1		ns
^t PLH	В	А	1.5	3.9	6.8	1.6	3.9	6.6	ns
^t PHL		^	1.2	2.8	4.5	1.3	2.8	4.5	115
^t PLH	LEBA	А	2.3	3.8	6.1	2.4	3.8	5.8	ns
^t PHL	LLDA	A	1.9	3	4.8	2	3	4.6	115
^t PLH	CLKBA	Δ	2.5	4	6.3	2.6	4	6	ne
^t PHL	CENDA	Α	2.1	3.4	5.1	2.2	3.4	4.9	ns
^t PLH	CLKOUT	CLKIN	7.1	9.9	14.7	7.3	9.9	14.3	ns
^t PHL	OLINOOT	OLIMIY	5.8	8	11.6	6	8	11.5	113
t _{en}	 OEBA	A or CLKIN	2.7	5.3	8.1	2.8	5.3	7.8	ns
^t dis	OLDA	A OI OLININ	2.6	4.3	6.7	2.7	4.3	6.4	110

 $[\]dagger$ All typical values are at V_{CC} (3.3 V) = 3.3 V, V_{CC} (5 V) = 5 V, T_A = 25°C.

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PARAMETER MEASUREMENT INFORMATION $V_{TT} = 1.2 \text{ V}$, $V_{REF} = 0.8 \text{ V}$ FOR GTL AND $V_{TT} = 1.5 \text{ V}$, $V_{REF} = 1 \text{ V}$ FOR GTL+



† All control inputs are TTL levels.

NOTES: A. C_I includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



IMPORTANT NOTICE

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